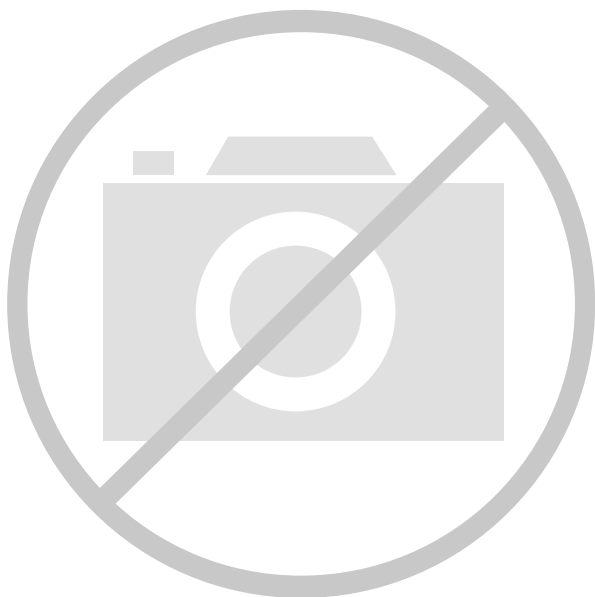




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Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	20 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	-
Number of Macrocells	512
Number of Gates	-
Number of I/O	160
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/m5lv-512-160-20yi



Table 1. MACH 5 Device Features ¹

Feature	M5-128/1 M5LV-128		M5-192/1	M5-256/1 M5LV-256		M5-320 M5LV-320		M5-384 M5LV-384		M5-512 M5LV-512	
Supply Voltage (V)	5	3.3	5	5	3.3	5	3.3	5	3.3	5	3.3
Macrocells	128	128	192	256	256	320	320	384	384	512	512
Maximum User I/O Pins	120	120	120	160	160	192	160	160	160	256	256
t _{PD} (ns)	5.5	5.5	5.5	5.5	5.5	6.5	6.5	6.5	6.5	6.5	6.5
t _{SS} (ns)	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0
t _{COS} (ns)	4.5	4.5	4.5	4.5	4.5	5.0	5.0	5.0	5.0	5.0	5.0
f _{CNT} (MHz)	182	182	182	182	182	167	167	167	167	167	167
Typical Static Power (mA)	35	35	45	55	55	70	70	75	75	100	100
IEEE 1149.1 Boundary Scan Compliant	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
PCI-Compliant	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes

Note:

1. "M5-xxx" is for 5-V devices. "M5LV-xxx" is for 3.3-V devices.

GENERAL DESCRIPTION

The MACH[®] 5 family consists of a broad range of high-density and high-I/O Complex Programmable Logic Devices (CPLDs). The fifth-generation MACH architecture yields fast speeds at high CPLD densities, low power, and supports additional features such as in-system programmability, Boundary Scan testability, and advanced clocking options (Table 1). The MACH 5 family offers 5-V (M5-xxx) and 3.3-V (M5LV-xxx) operation.

Manufactured in state-of-the-art ISO 9000 qualified fabrication facilities on E²CMOS process technologies, MACH 5 devices are available with pin-to-pin delays as fast as 5.5 ns (Table 2). The 5.5, 6.5, 7.5, 10, and 12-ns devices are compliant with the *PCI Local Bus Specification*.

Select devices have been discontinued.
See Ordering Information section for product status.

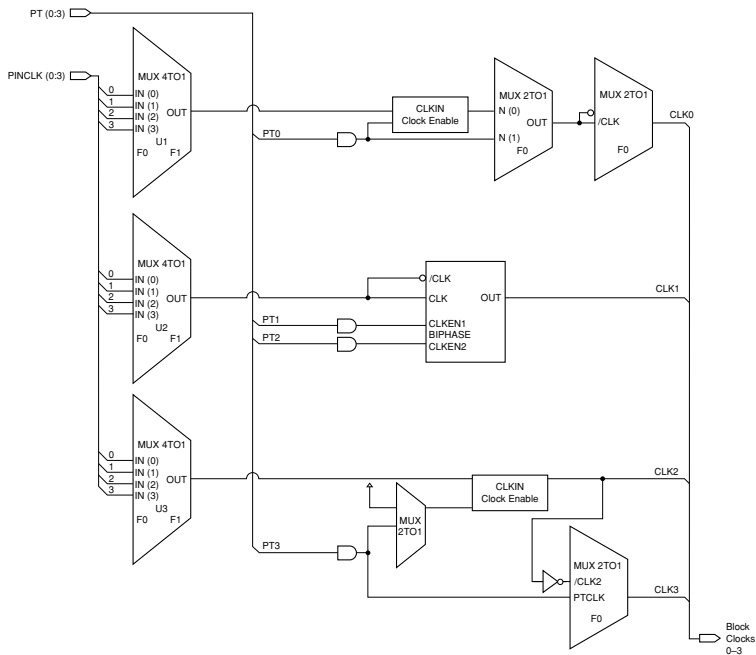
- ◆ Global clock (0, 1, 2, or 3) with positive and negative edge clock enable (biphase)

Clock Line 2 Options

- ◆ Global clock (0, 1, 2, or 3) with clock enable

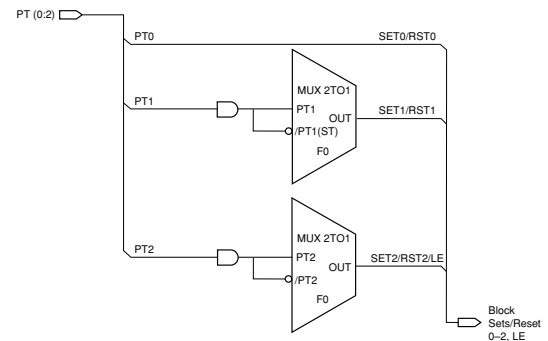
Clock Line 3 Options

- ◆ Complement of clock line 2 (same clock enable)
- ◆ Product-term clock (if clock line 2 does not use clock enable)



20446G-004

Figure 4. Clock Generator



20446G-005

Figure 5. Set/Reset Generator

The set/reset generation portion of the control generator (Figure 5) creates three set/reset lines for the PAL block. Each macrocell can choose one of these three lines or choose no set/reset at all. All three lines can be configured for product term set/reset and two of the three lines can be configured as sum term set/reset and one of the lines can be configured as product-term or sum-term latch enable. While the set/reset signals are generated in the control generator, whether that signal sets or resets a flip-flop is determined within the individual macrocell. The same signal can set one flip-flop and reset another. PT2 or /PT2 can also be used as a latch enable for macrocells configured as latches.

**Select devices have been discontinued.
See Ordering Information section for product status.**

OE Generator

There is one output enable (OE) generator per PAL block that generates two product-term driven output enables. Each I/O cell is simply an output buffer. Each I/O cell within the PAL block can choose to be permanently enabled, permanently disabled, or choose one of the two product term output enables per PAL block (Figure 6).

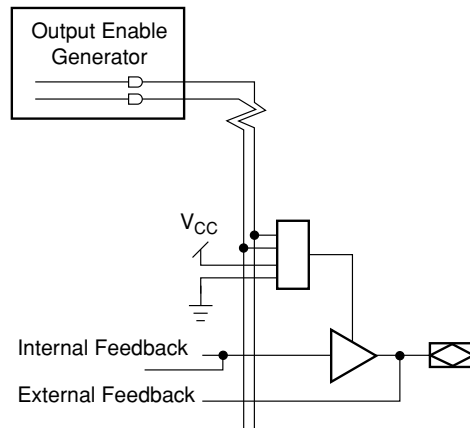


Figure 6. Output Enable Generator and I/O Cell

20446G-006

Select devices have been discontinued.
See Ordering Information section for product status.

SAFE FOR MIXED SUPPLY VOLTAGE SYSTEM DESIGNS ¹

Both the 3.3-V and 5-V V_{CC} MACH 5 devices are safe for mixed supply voltage system designs. The 5-V devices will not overdrive 3.3-V devices above the output voltage of 3.3 V, while they accept inputs from other 3.3-V devices. The 3.3-V devices will accept inputs up to 5.5 V. Both the 3.3-V and 5-V versions have the same high-speed performance and provide easy-to-use mixed-voltage design capability.

Note:

1. Excludes original M5-128, M5-192, and M5-256 while M5-128/1, M3-192/1 and M5-256/1 are supported. Please refer to Application Note titled "Hot Socketing and Mixed Supply Design with MACH 4 and MACH 5 Devices".

BUS-FRIENDLY INPUTS AND I/OS

All MACH 5 devices have inputs and I/Os which feature the Bus-Friendly circuitry incorporating two inverters in series which loop back to the input. This double inversion weakly holds the input at its last driven logic state. While it is a good design practice to tie unused pins to a known state, the Bus-Friendly input structure pulls pins away from the input threshold voltage where noise can cause high-frequency switching. At power-up, the Bus-Friendly latches are reset to a logic level "1." For the circuit diagram, please refer to the document entitled *MACH Endurance Characteristics* on the Lattice Data Book CD-ROM or Lattice web site.

POWER MANAGEMENT

There are 4 power/speed options in each MACH 5 PAL block (Table 5). The speed and power tradeoff can be tailored for each design. The signal speed paths in the lower-power PAL blocks will be slower than those in the higher-power PAL blocks. This feature allows speed critical paths to run at maximum frequency while the rest of the signal paths operate in a lower-power mode. In large designs, there may be several different speed requirements for different portions of the design.

Table 5. Power Levels

High Speed/High Power	100% Power
Medium High Speed/Medium High Power	67% Power
Medium Low Speed/Medium Low Power	40% Power
Low Speed/Low Power	20% Power

PROGRAMMABLE SLEW RATE

Each MACH 5 device I/O has an individually programmable output slew rate control bit. Each output can be individually configured for the higher speed transition (3 V/ns) or for the lower noise transition (1 V/ns). For high-speed designs with long, unterminated traces, the slow-slew rate will introduce fewer reflections, less noise, and keep ground bounce to a minimum. For designs with short traces or well terminated lines, the fast slew rate can be used to achieve the highest speed. The slew rate is adjusted independent of power.

POWER-UP RESET/SET

All flip-flops power up to a known state for predictable system initialization. If a macrocell is configured to SET on a signal from the control generator, then that macrocell will be SET during device power-up. If a macrocell is configured to RESET on a signal from the control generator or is not configured for set/reset, then that macrocell will RESET on power-up. To guarantee initialization values, the V_{CC} rise must be monotonic and the clock must be inactive until the reset delay time has elapsed.

Select devices have been discontinued. See Ordering Information section for product status.



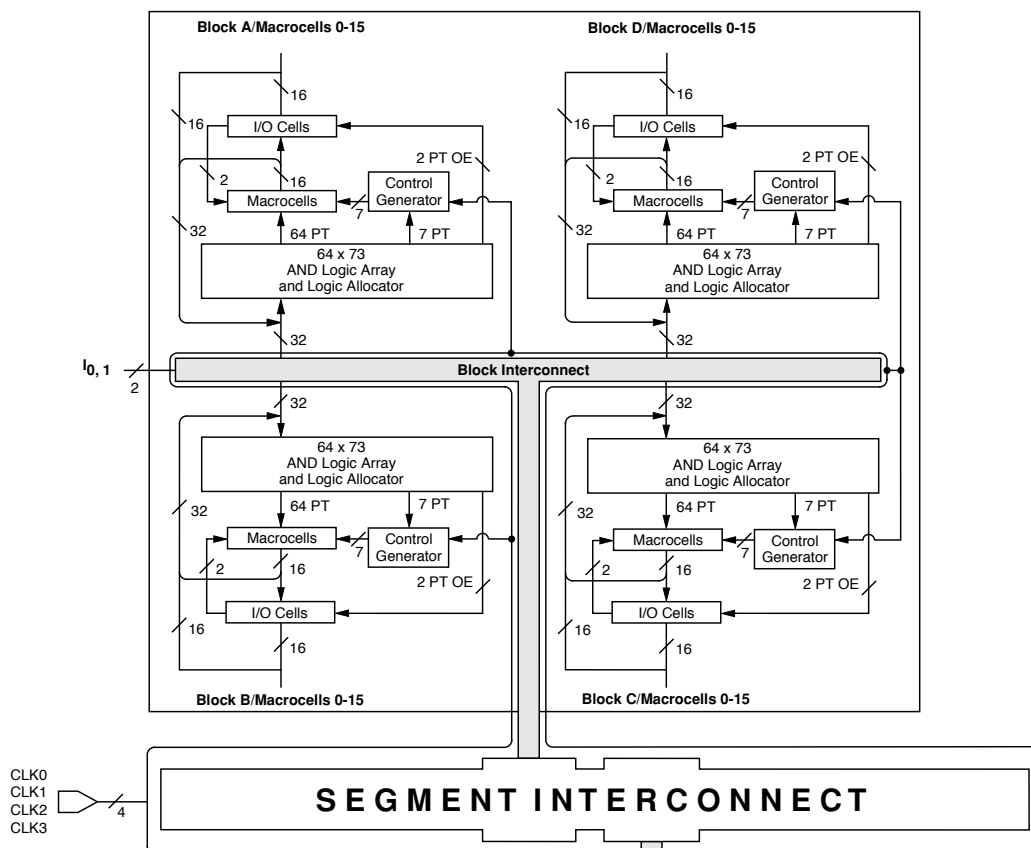
SECURITY BIT

A programmable security bit is provided on the MACH 5 devices as a deterrent to unauthorized copying of the array configuration patterns. Once programmed, this bit defeats readback of the programmed pattern by a device programmer, securing proprietary designs from competitors. Programming and verification are also defeated by the security bit. The bit can only be reset by erasing the entire device.

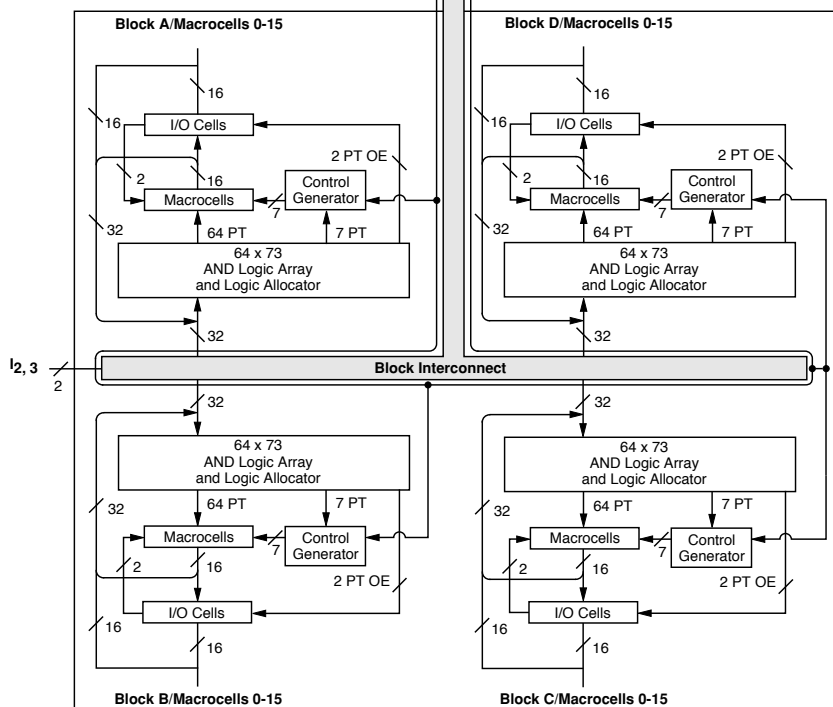
**Select devices have been discontinued.
See Ordering Information section for product status.**

BLOCK DIAGRAM — M5(LV)-128/XXX

SEGMENT 0



SEGMENT INTERCONNECT

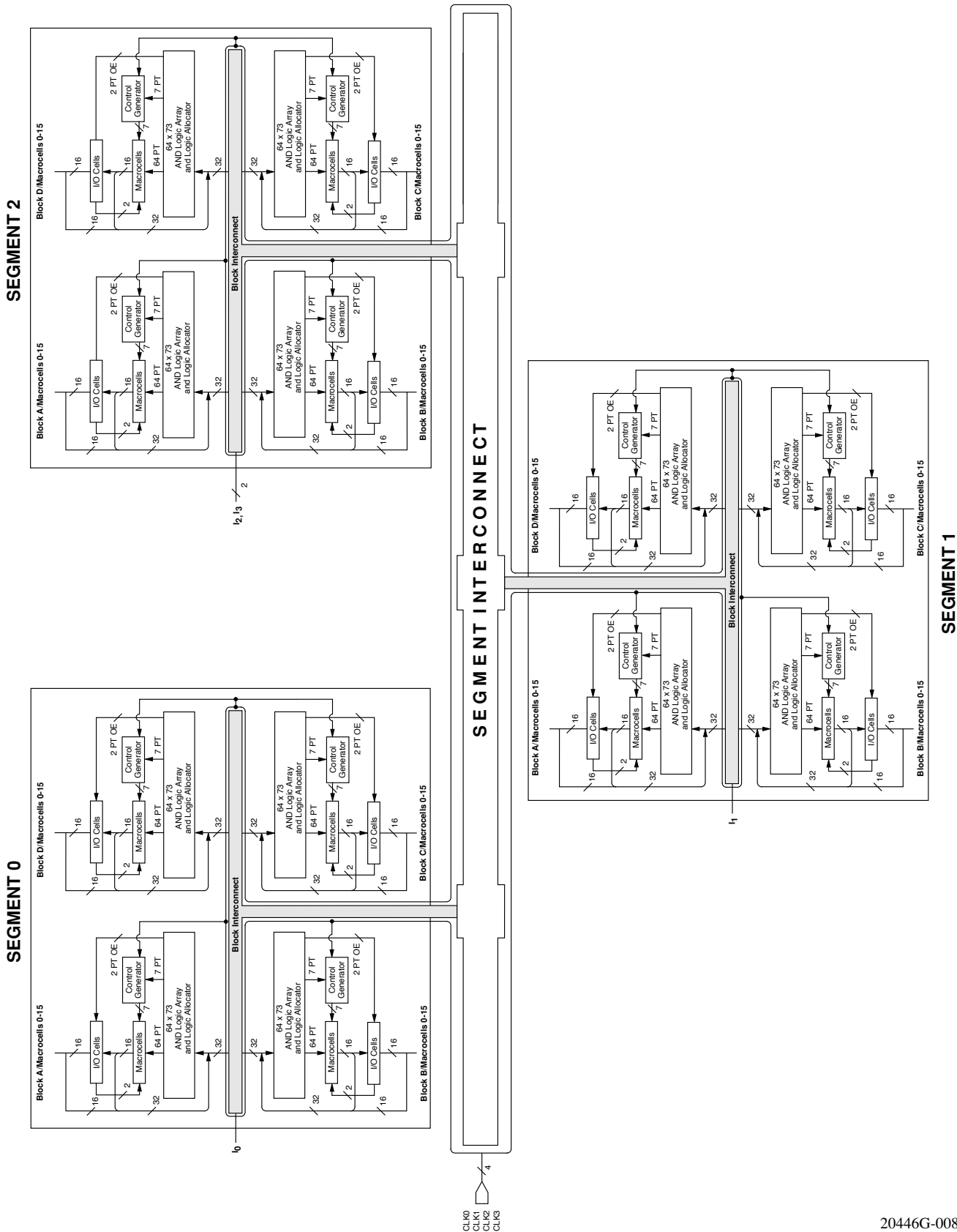


SEGMENT 1

20446G-007

Select devices have been discontinued.
See Ordering Information section for product status.

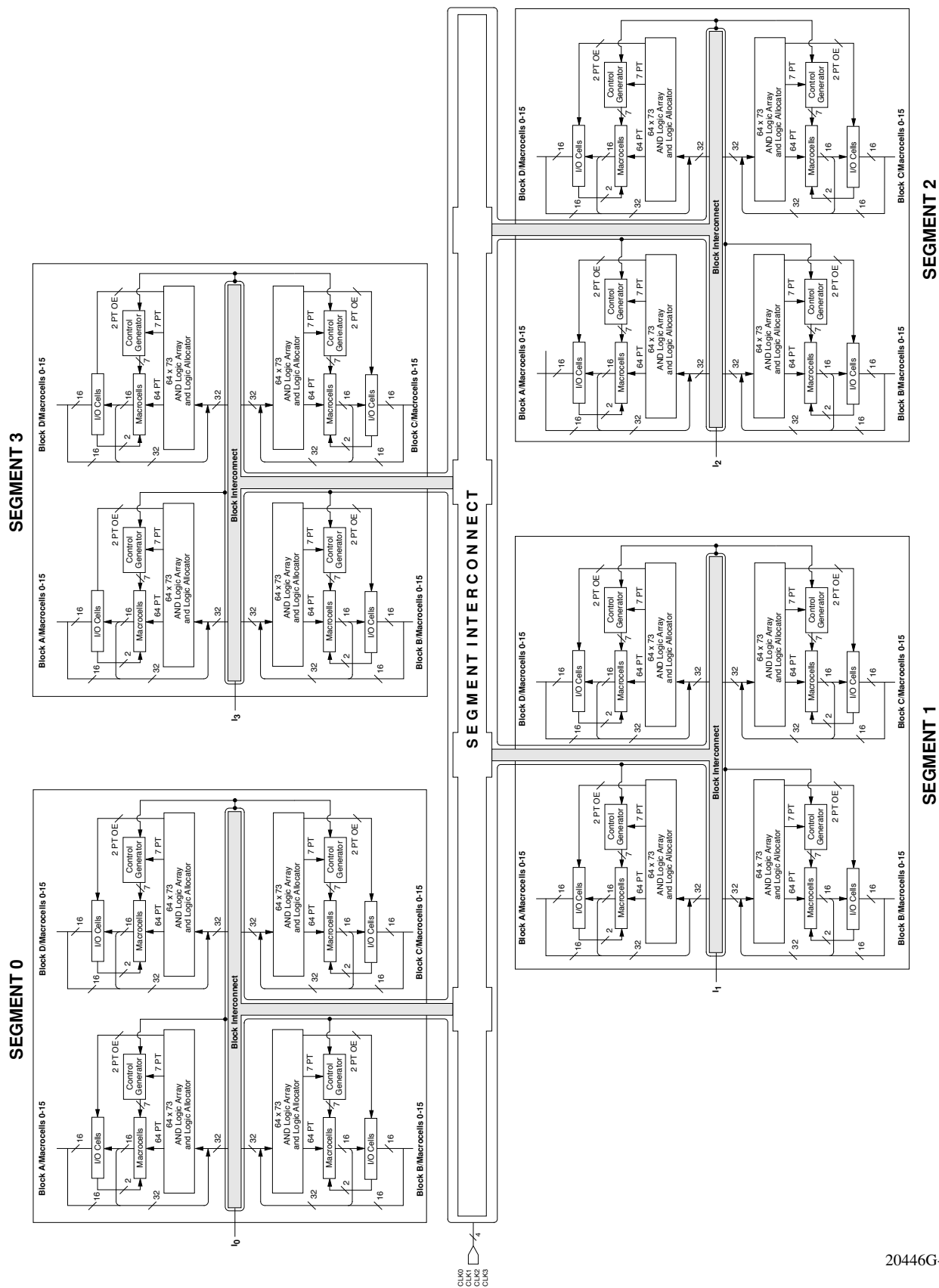
BLOCK DIAGRAM — M5-192/XXX



Select devices have been discontinued.
See Ordering Information section for product status.

20446G-008

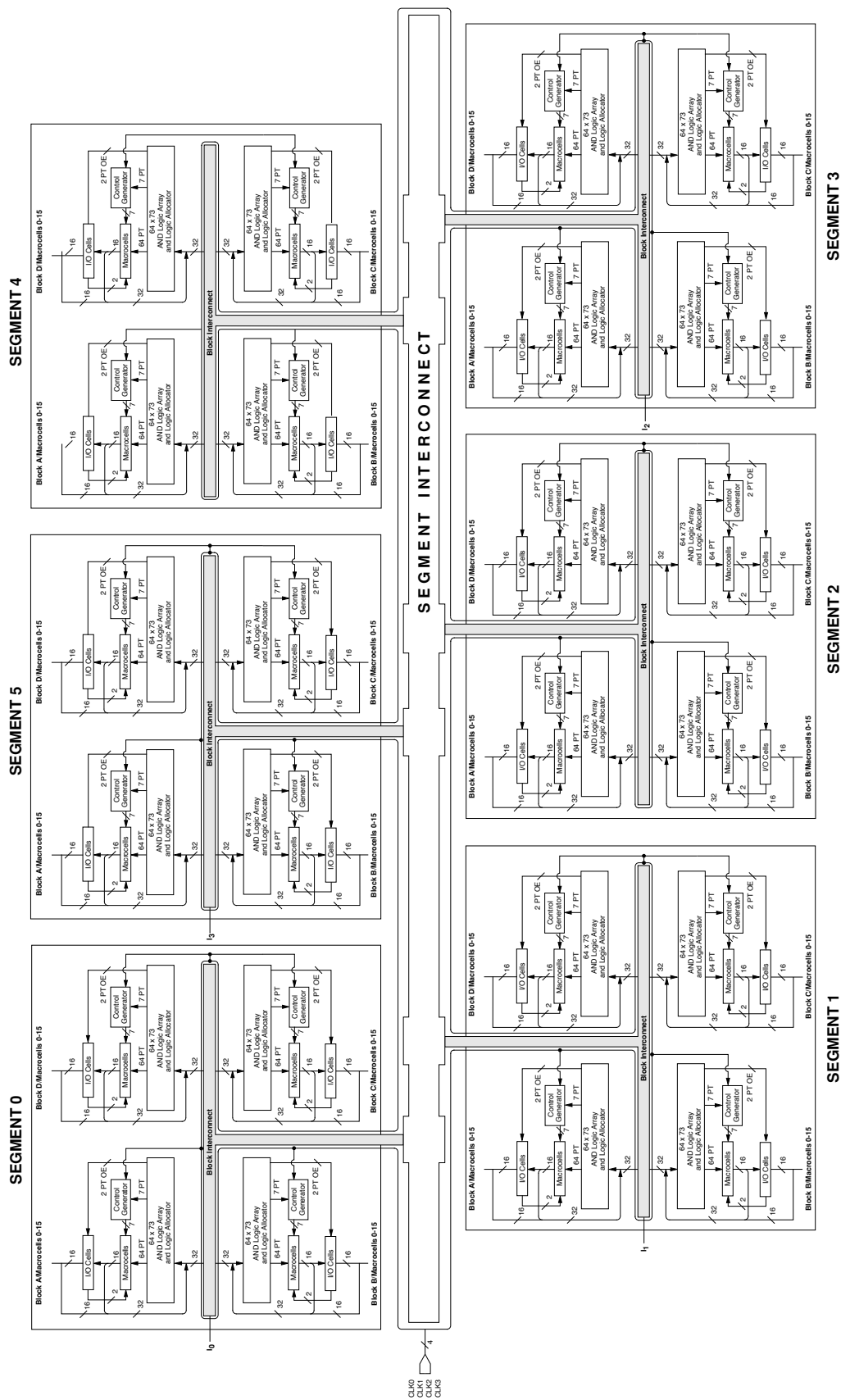
BLOCK DIAGRAM — M5(LV)-256/XXX



Select devices have been discontinued.
See Ordering Information section for product status.

20446G-009

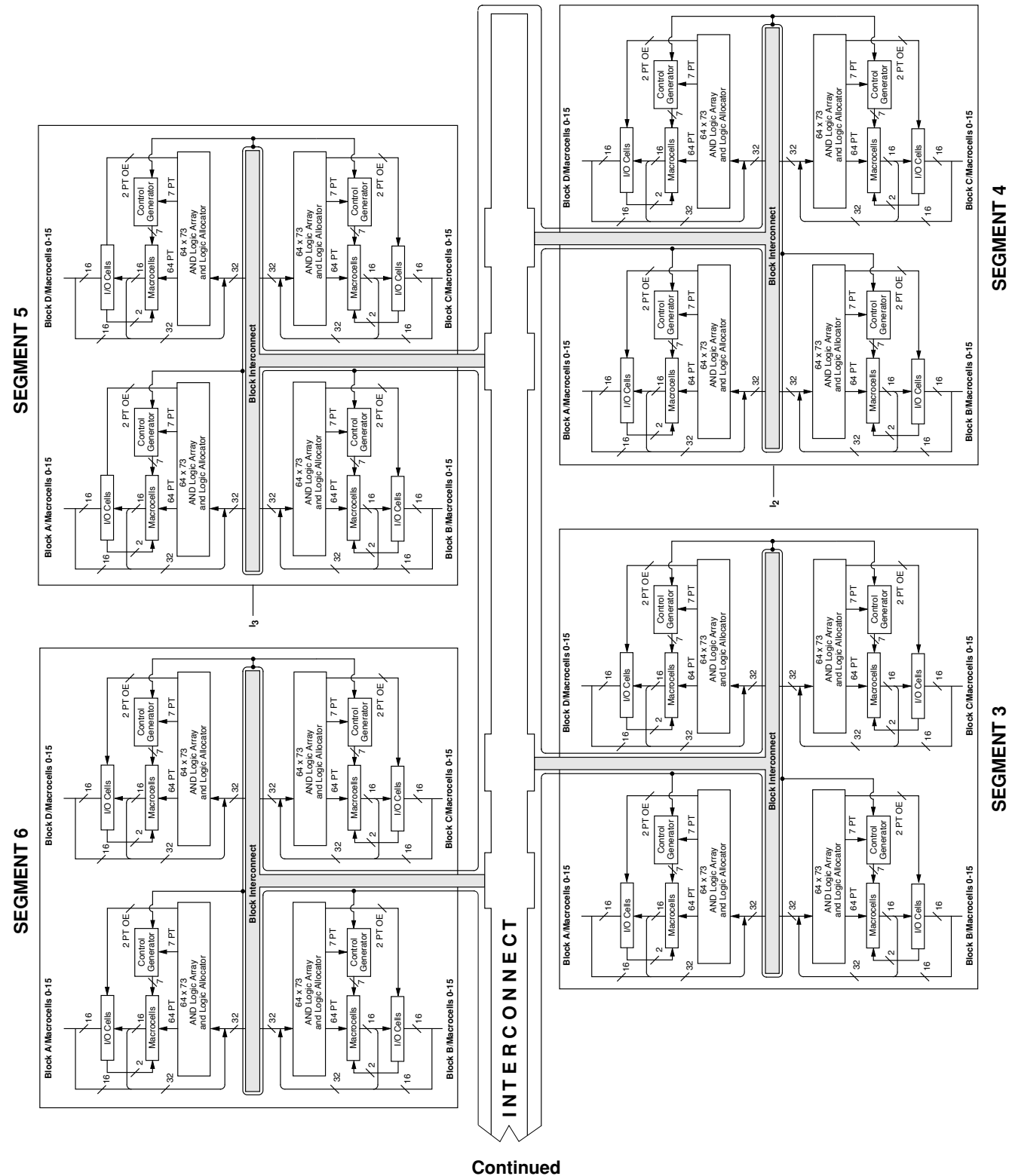
BLOCK DIAGRAM — M5(LV)-384/XXX



Select devices have been discontinued.
See Ordering Information section for product status.

20446G-011

BLOCK DIAGRAM — M5(LV)-512/XXX



Select devices have been discontinued.
See Ordering Information section for product status.

Continued

ABSOLUTE MAXIMUM RATINGS

M5LV

Storage Temperature. -65°C to +150°C
Device Junction Temperature. +130°C
Supply Voltage
with Respect to Ground -0.5 V to +4.5 V
DC Input Voltage -0.5 V to 5.5 V
Static Discharge Voltage 2000 V
Latchup Current (-40°C to +85°C) 200 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature (T_A)
Operating in Free Air. 0°C to +70°C
Supply Voltage (V_{CC})
with Respect to Ground. +3.0 V to +3.6 V

Industrial (I) Devices

Ambient Temperature (T_A)
Operating in Free Air. -40°C to +85°C
Supply Voltage (V_{CC})
with Respect to Ground. +3.0 V to +3.6 V
Operating ranges define those limits between which the functionality of the device is guaranteed.

Select devices have been discontinued.
See Ordering Information section for product status.

3.3-V DC CHARACTERISTICS OVER OPERATING RANGES

Parameter Symbol	Parameter Description	Test Description		Min	Max	Unit
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min}$	$I_{OH} = -100 \mu A$	$V_{CC} - 0.2$		V
		$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = 3.2 \text{ mA}$	2.4		V
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min}$	$I_{OL} = 100 \mu A$		0.2	V
		$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 16 \text{ mA (Note 1)}$		0.5	V
V_{IH}	Input HIGH Voltage	$V_{OUT} \geq V_{OH} \text{ Min or } V_{OUT} \leq V_{OL} \text{ Max (Note 2)}$		2.0	5.5	V
V_{IL}	Input LOW Voltage	$V_{OUT} \geq V_{OH} \text{ Min or } V_{OUT} \leq V_{OL} \text{ Max (Note 2)}$		-0.3	0.8	V
I_{IH}	Input HIGH Leakage Current	$V_{IN} = 3.6, V_{CC} = \text{Max (Note 3)}$			10	μA
I_{IL}	Input LOW Leakage Current	$V_{IN} = 0, V_{CC} = \text{Max (Note 3)}$			-10	μA
I_{OZH}	Off-State Output Leakage Current HIGH	$V_{OUT} = 3.6, V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL} \text{ (Note 3)}$			10	μA
I_{OZL}	Off-State Output Leakage Current LOW	$V_{OUT} = 0, V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL} \text{ (Note 3)}$			-10	μA
I_{SC}	Output Short-Circuit Current	$V_{OUT} = 0.5 V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL} \text{ (Note 4)}$		-15	-160	mA

Notes:

1. Total I_{OL} between ground pins should not exceed 64 mA.
2. These are absolute values with respect to device ground, and all overshoots due to system and/or tester noise are included.
3. I/O pin leakage is the worst case of I_{IL} and I_{OZL} or I_{IH} and I_{OZH} .
4. Not more than one output should be shorted at one time. Duration of the short-circuit should not exceed one second.

M5(LV) TIMING PARAMETERS OVER OPERATING RANGES¹ (CONTINUED)

		-5		-6		-7		-10		-12		-15		-20		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Frequency:																
f _{MAX}	External feedback, PAL block level. Min of 1/(t _{WLS} + t _{WHS}) or 1/(t _{SS} + t _{COS})	133		125		100		83.3		71.4		55.6		45.5		MHz
	Internal feedback, PAL block level. Min of 1/(t _{WLS} + t _{WHS}) or 1/(t _{SS} + t _{COSi})	182		167		125		100		83.3		62.5		50.0		MHz
	No feedback PAL block level. Min of 1/(t _{WLS} + t _{WHS}) or 1/(t _{SS} + t _{HS})	200		167		167		125		100		83.3		83.3		MHz
f _{MAXA}	External feedback, PAL block level. Min of 1/(t _{WLA} + t _{WHA}) or 1/(t _{SA} + t _{COA})	91		91		71.4		58.8		47.6		41.7		35.7		MHz
	Internal feedback, PAL block level. Min of 1/(t _{WLA} + t _{WHA}) or 1/(t _{SA} + t _{COAi})	111		111		83.3		66.7		52.6		45.5		38.5		MHz
	No feedback, PAL block level. Min of 1/(t _{WLA} + t _{WHA}) or 1/(t _{SA} + t _{HA})	167		125		125		100		83.3		71.4		62.5		MHz
f _{MAXI}	Maximum input register frequency 1/(t _{SIRS} + t _{HIRS}) or 1/(2 x t _{WICW})	167		125		125		100		83.3		71.4		62.5		MHz

Notes:

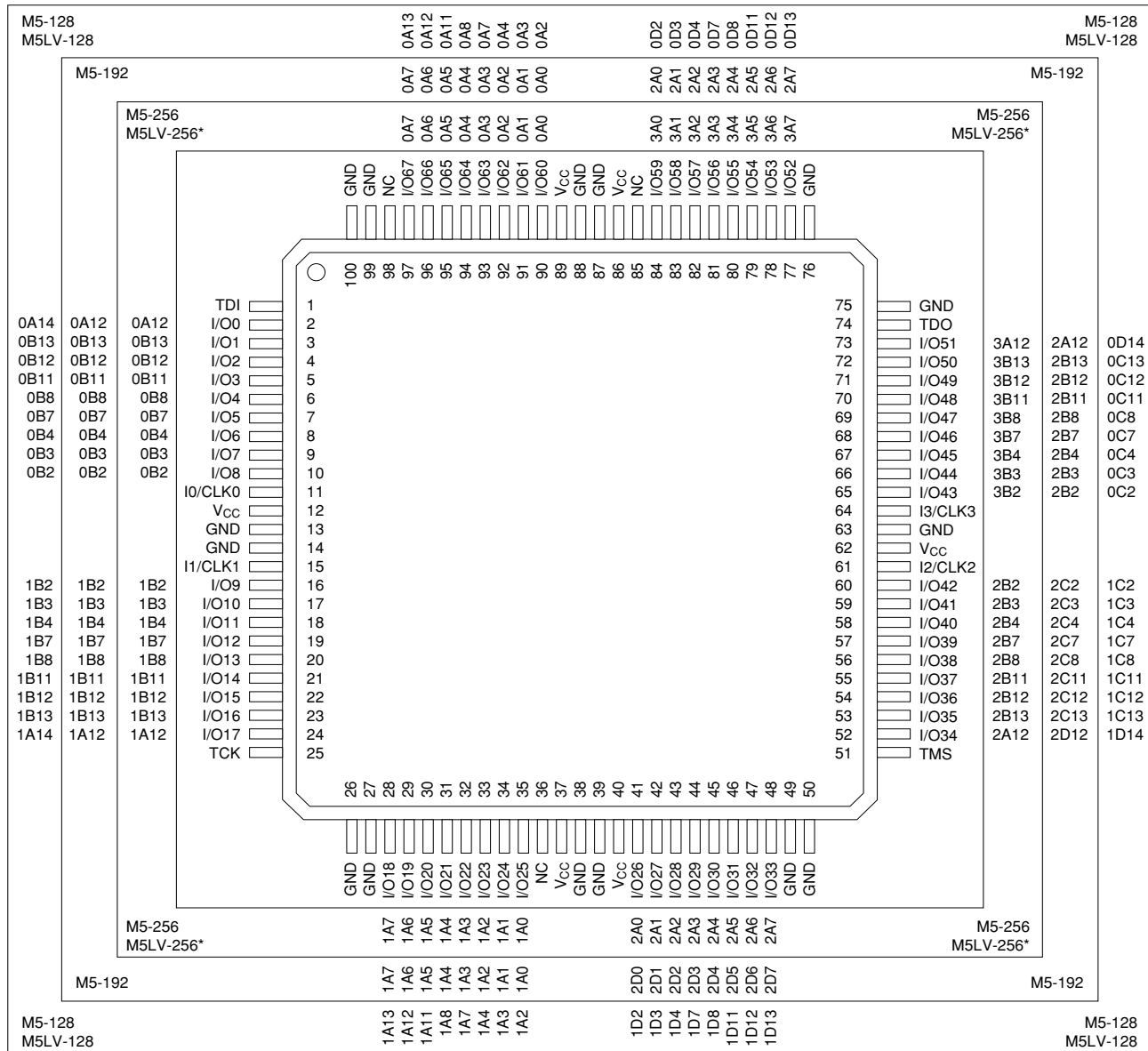
- See "MACH Switching Test Circuits" documentation on the Lattice Data Book CD-ROM or Lattice web site.
- Numbers in parentheses are for M5-128, M5-192, M5-256.
- If a signal is used as both a clock and a logic array input, then the maximum input frequency applies ($f_{MAX}/2$).

Select devices have been discontinued.
See Ordering Information section for product status.

100-PIN TQFP CONNECTION DIAGRAM – 68 I/O

Top View

100-Pin TQFP (68 I/O)



*Package obsolete, contact factory.

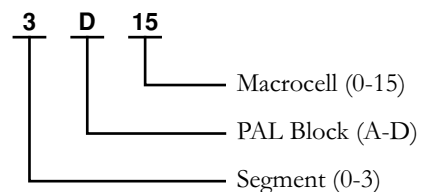
Select devices have been discontinued.
See Ordering Information section for product status.

20446G-017

Pin Designations

CLK = Clock
GND = Ground
I = Input
I/O = Input/Output
NC = No Connect

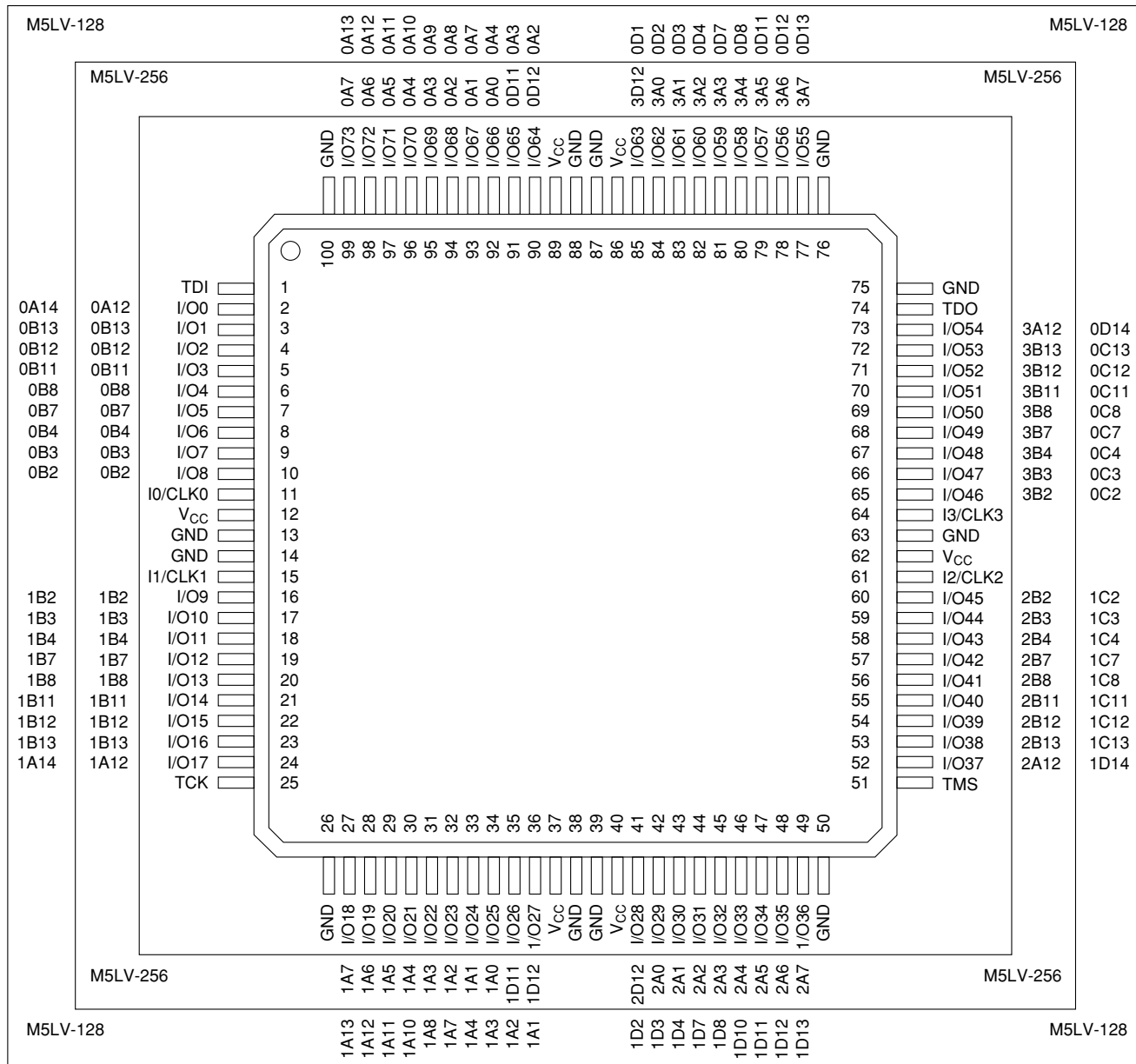
V_{CC} = Supply Voltage
TDI = Test Data In
TCK = Test Clock
TMS = Test Mode Select
TDO = Test Data Out



100-PIN TQFP CONNECTION DIAGRAM – 74 I/O

Top View

100-Pin TQFP (74 I/O)



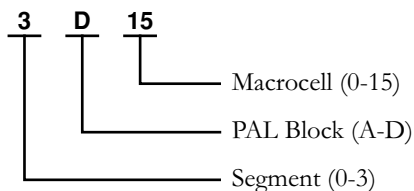
Select devices have been discontinued.
See Ordering Information section for product status.

20446G-018

Pin Designations

CLK = Clock
GND = Ground
I = Input
I/O = Input/Output
NC = No Connect

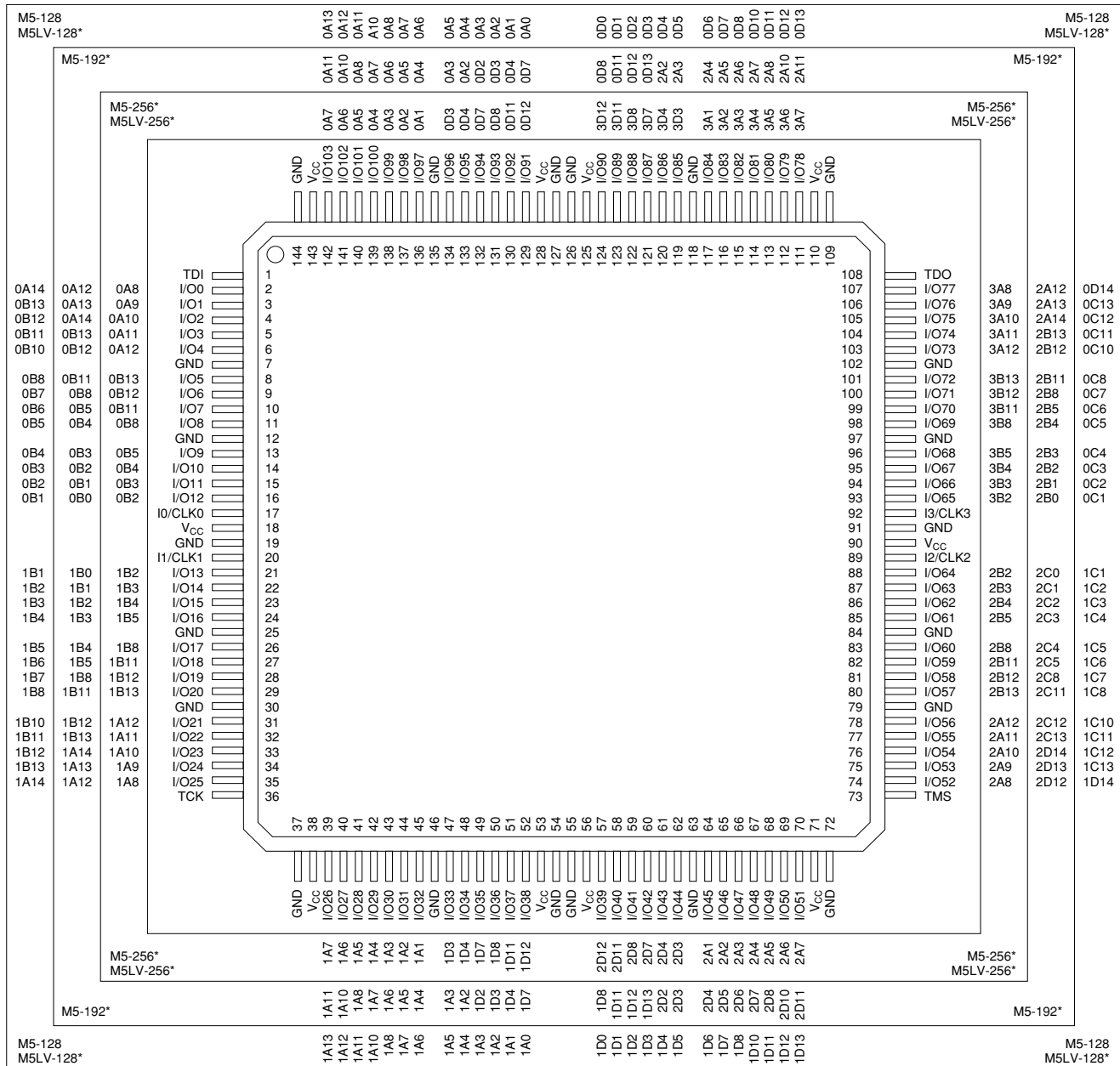
V_{CC} = Supply Voltage
TDI = Test Data In
TCK = Test Clock
TMS = Test Mode Select
TDO = Test Data Out



144-PIN PQFP CONNECTION DIAGRAM

Top View

144-Pin PQFP



Select devices have been discontinued.
See Ordering Information section for product status.

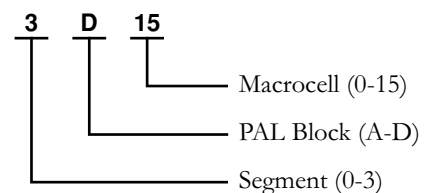
*Package obsolete, contact factory.

20446G-019

Pin Designations

CLK = Clock
GND = Ground
I = Input
I/O = Input/Output
NC = No Connect

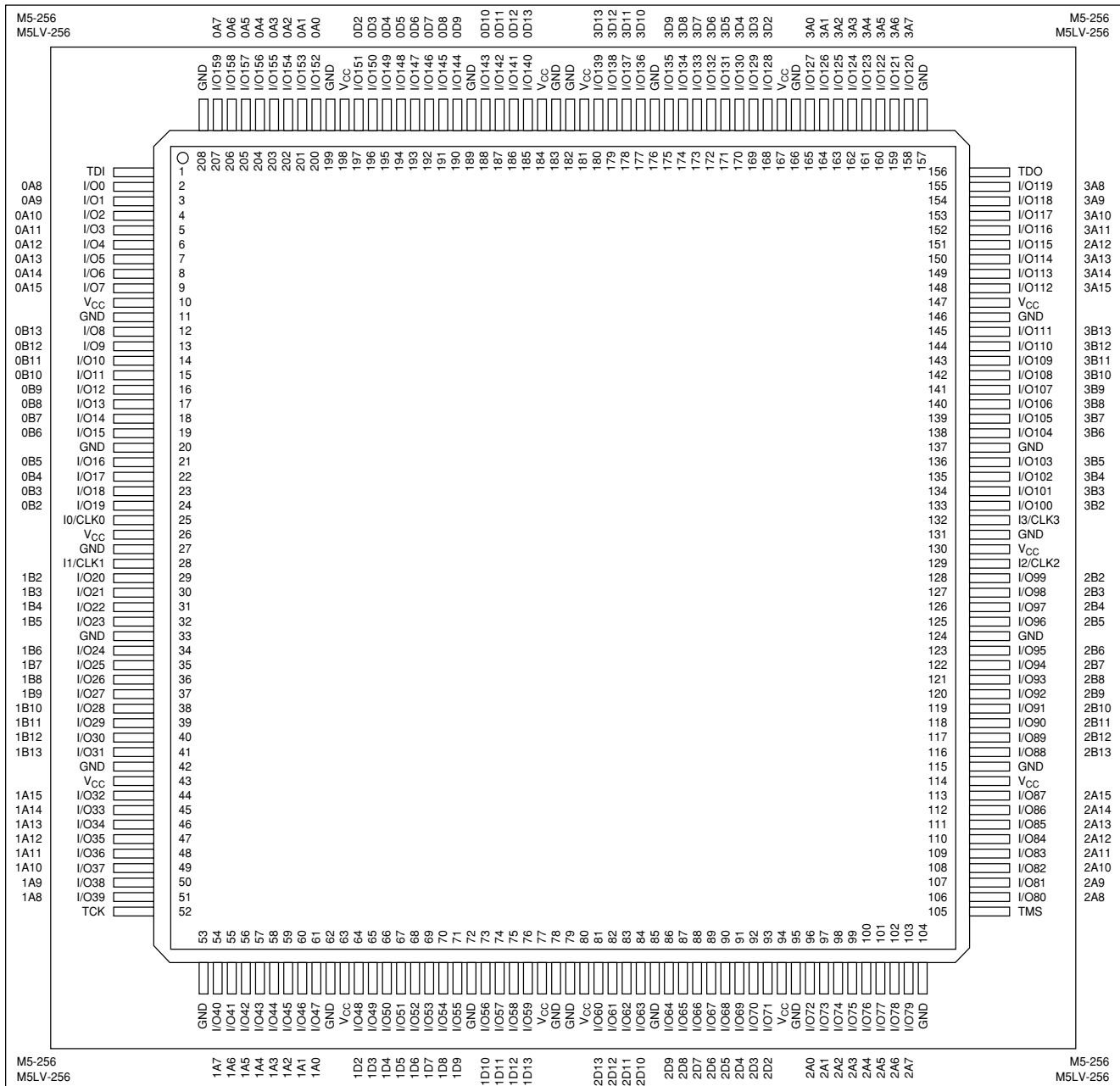
V_{CC} = Supply Voltage
TDI = Test Data In
TCK = Test Clock
TMS = Test Mode Select
TDO = Test Data Out



208-PIN PQFP CONNECTION DIAGRAM

Top View

208-Pin PQFP (256 Macrocells)

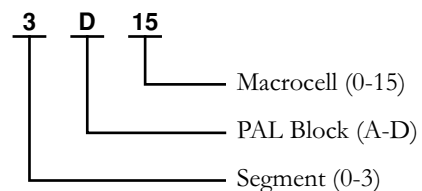


Select devices have been discontinued.
See Ordering Information section for product status.

20446G-023

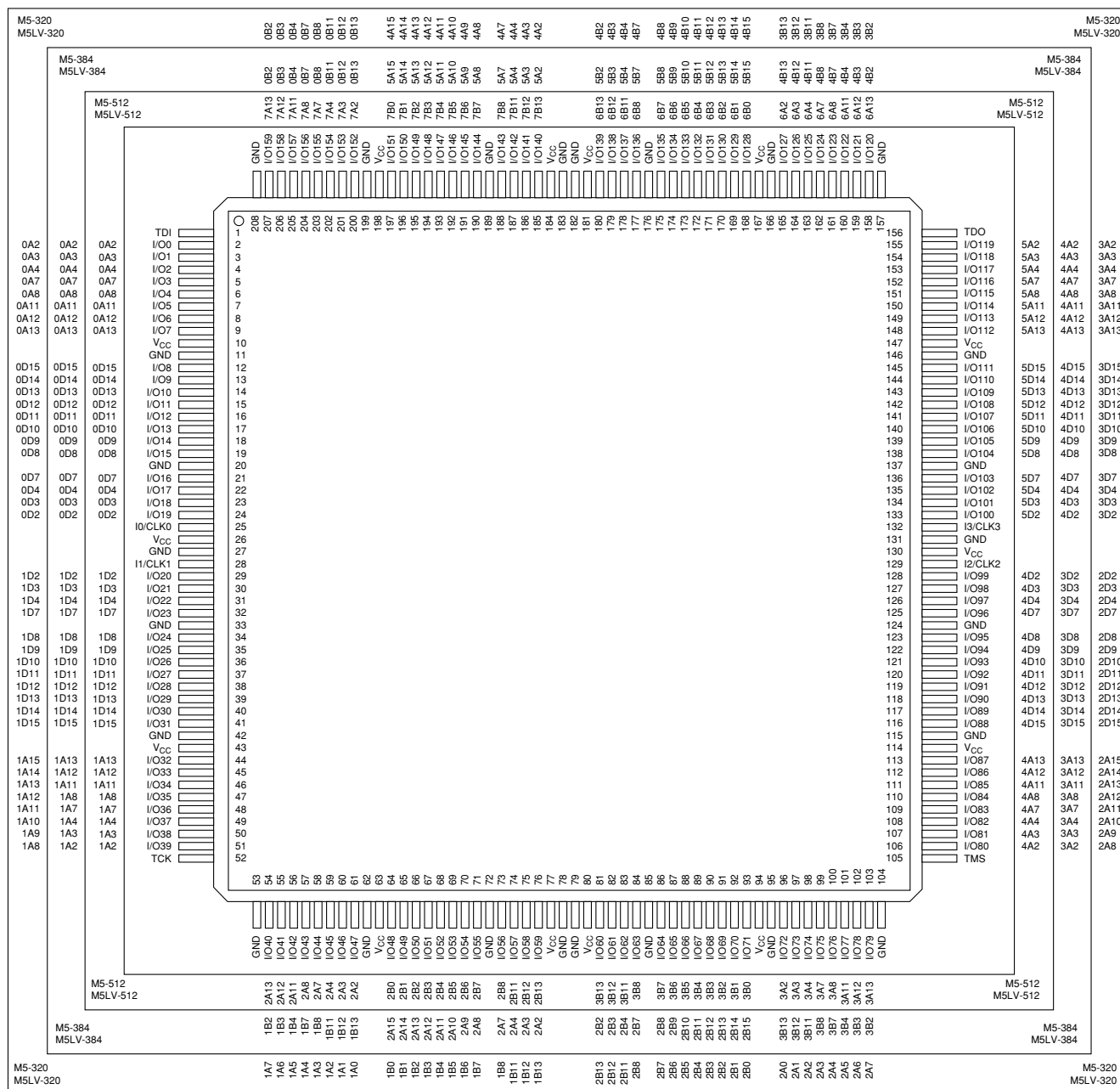
Pin Designations

CLK = Clock	VCC = Supply Voltage
GND = Ground	TDI = Test Data In
I = Input	TCK = Test Clock
I/O = Input/Output	TMS = Test Mode Select
NC = No Connect	TDO = Test Data Out



208-PIN PQFP (WITH INTERNAL HEAT SPREADER) CONNECTION DIAGRAM Top View

208-Pin PQFP (320, 384, 512 Macrocells)



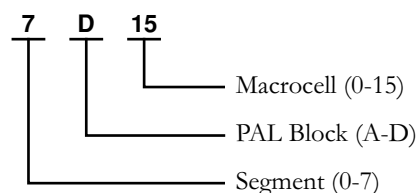
Select devices have been discontinued.
See Ordering Information section for product status.

20446G-024

Pin Designations

CLK = Clock
GND = Ground
I = Input
I/O = Input/Output
NC = No Connect

V_{CC} = Supply Voltage
TDI = Test Data In
TCK = Test Clock
TMS = Test Mode Select
TDO = Test Data Out



256-BALL BGA CONNECTION DIAGRAM — M5-320

Bottom View (I/O Pin-outs)

256-Ball BGA

	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	GND	I/O11	GND	I/O44	I/O58	GND	I/O70	I/O76	GND	GND	GND	GND	I/O108	I/O116	GND	I/O128	I/O134	GND	GND	GND	A
B	GND	I/O12	I/O28	I/O45	I/O59	I/O64	I/O71	I/O77	I/O84	I/O90	I/O96	I/O102	I/O109	I/O117	I/O122	I/O129	I/O135	I/O148	I/O164	GND	B
C	I/O0	I/O13	V _{CC}	I/O46	I/O60	I/O65	I/O72	I/O78	I/O85	I/O91	I/O97	I/O103	I/O110	I/O118	I/O123	I/O130	I/O136	V _{CC}	I/O165	I/O181	C
D	I/O1	I/O14	I/O29	V _{CC}	V _{CC}	I/O66	V _{CC}	I/O79	I/O86	I/O92	I/O98	I/O104	I/O111	V _{CC}	I/O124	V _{CC}	V _{CC}	I/O149	I/O166	I/O182	D
E	I/O2	I/O15	I/O30	TDI													TDI	I/O150	I/O167	I/O183	E
F	GND	I/O16	I/O31	I/O47													I/O137	I/O151	I/O168	GND	F
G	I/O3	I/O17	I/O32	V _{CC}													V _{CC}	I/O152	I/O169	I/O184	G
H	GND	I/O18	I/O33	I/O48													I/O138	I/O153	I/O170	GND	H
J	I/O4	I/O19	I/O34	I/O49													I/O139	I/O154	I/O171	I/O185	J
K	GND	I/O20	I/O35	I/O50													I/O140	I/O155	I/O172	I/O186	K
L	I/O5	I/O21	I/O36	I/O51													I/O141	I/O156	I/O173	GND	L
M	I/O6	I/O22	I/O37	I/O52													I/O142	I/O157	I/O174	I/O187	M
N	GND	I/O23	I/O38	I/O53													I/O143	I/O158	I/O175	GND	N
P	I/O7	I/O24	I/O39	V _{CC}													V _{CC}	I/O159	I/O176	I/O188	P
R	GND	I/O25	I/O40	I/O54													I/O144	I/O160	I/O177	GND	R
T	I/O8	I/O26	I/O41	TCK													TMS	I/O161	I/O178	I/O189	T
U	I/O9	I/O27	I/O42	V _{CC}													V _{CC}	I/O162	I/O179	I/O190	U
V	I/O10	I/O28	V _{CC}	I/O55													I/O145	V _{CC}	I/O180	I/O191	V
W	GND	I/O29	I/O43	I/O56													I/O146	I/O163	I/O181	GND	W
Y	GND	I/O30	GND	I/O57													I/O147	GND	I/O182	I/O192	Y

Pin Designations

CLK	=	Clock
GND	=	Ground
I	=	Input
I/O	=	Input/Output
NC	=	No Connect
V _{CC}	=	Supply Voltage
TDI	=	Test Data In
TCK	=	Test Clock
TMS	=	Test Mode Select
TDO	=	Test Data Out

Select devices have been discontinued.
See Ordering Information section for product status.

20446G-026

352-BALL BGA CONNECTION DIAGRAM — M5-512, M5LV-512

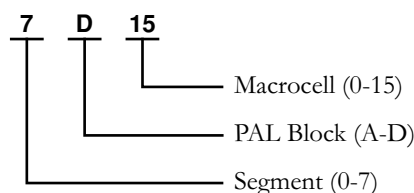
Bottom View (Macrocell Association)

352-Ball BGA

	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	AA	AB	AC	AD	AE	AF
1	NC	NC	NC	GND	NC	5A12	GND	5D15	5D11	GND	5D6	5D3	I3/CLK3	GND	4D1	4D5	4D9	GND	4D15	4A13	GND	NC	4A6	GND	NC	NC
2	NC	NC	NC	5A2	5A5	5A9	5A14	5A15	5D13	5D10	5D8	5D4	5D0	4D0	4D2	4D6	4D10	4D13	4A15	4A12	4A9	4A8	4A3	4A1	GND	GND
3	GND	GND	NC	5A1	5A4	5A7	5A8	5A10	5A13	5D14	5D9	5D5	5D1	I2/CLK2	4D4	4D7	4D11	4D14	4A14	4A10	4A7	4A5	4A2	TMS	NC	NC
4	NC	6A14	NC	TDO	5A0	5A3	5A6	VCC	5A11	VCC	5D12	5D7	5D2	VCC	4D3	4D8	4D12	VCC	4A11	VCC	4A4	4A0	VCC	3A15	3A13	3A12
5	GND	6A12	6A13	VCC																						
6	NC	6A9	6A10	6A15																			3A14	3A11	3A9	GND
7	GND	6A6	6A8	6A11																			3A6	3A4	3A3	3A5
8	6A1	6A4	6A5	6A7																			3A2	3A1	3B0	NC
9	6B1	6A0	6A2	6A3																			VCC	3B1	3B2	GND
10	GND	6B2	6B0	VCC																			3B3	3B4	3B5	3B6
11	6B6	6B5	6B4	6B3																			3B7	3B8	3B9	3B10
12	6B10	6B9	6B8	6B7																			3B11	3B12	3B13	3B14
13	6B14	6B13	6B12	6B11																			VCC	2B15	3B15	GND
14	GND	7B15	6B15	VCC																			2B11	2B12	2B13	2B14
15	7B14	7B13	7B12	7B11																			2B7	2B8	2B9	2B10
16	NC	7B10	7B9	7B8																			2B3	2B4	2B5	2B6
17	7B7	7B6	7B5	7B4																			VCC	2B0	2B2	GND
18	GND	7B3	7B2	VCC																			2A3	2A2	2A0	2B1
19	7B1	7B0	7A1	7A4																			2A7	2A5	2A4	2A1
20	7A0	7A2	7A3	7A8																			2A11	2A8	2A6	GND
21	7A5	7A6	7A7	7A12																			2A15	2A10	2A9	NC
22	GND	7A9	7A11	7A15																			VCC	2A13	2A12	GND
23	7A10	7A13	7A14	VCC																			TCK	NC	2A14	NC
24	NC	NC	TDI	0A2	0A0	0A7	0A10	0A11	0D14	0D11	0D7	0D4	I0/CLK0	1D1	1D5	1D9	1D14	1A13	1A10	1A8	1A7	1A4	1A1	NC	GND	GND
25	GND	GND	0A1	0A3	0A8	0A9	0A12	0A15	0D13	0D10	0D6	0D2	0D0	1D0	1D4	1D8	1D10	1D13	1A15	1A14	1A9	1A5	1A2	NC	NC	NC
26	NC	NC	GND	0A6	NC	GND	0A13	0D15	GND	0D9	0D5	0D1	GND	I1/CLK1	1D3	1D6	GND	1D11	1D15	GND	1A12	NC	GND	NC	NC	NC

Pin Designations

- CLK = Clock
- GND = Ground
- I = Input
- I/O = Input/Output
- NC = No Connect
- VCC = Supply Voltage
- TDI = Test Data In
- TCK = Test Clock
- TMS = Test Mode Select
- TDO = Test Data Out



20446G-031

Select devices have been discontinued.
See Ordering Information section for product status.